## Application/Control No. O9/846,697 Applicant(s)/Patent Under Reexamination FERM ET AL. Examiner John A. McPherson Applicant(s)/Patent Under Reexamination FERM ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			
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	К	US-			
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## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U	"Resists in Microlithography", O'Brien et al., pages 325 to 376 of Microelectronics Processing: Chemical Engineering Aspects, American Chemical Society, 1989.						
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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